

Supporting Information

Multigenerational collision-induced dissociation for characterization of organic compounds

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Movie S1: Illustration of multigenerational CID on the Mathieu stability diagram. A single reverse rf scan is used with a fixed AC frequency (“hole” on the q axis of the Mathieu stability diagram) so that a single scan of the RF produces a multigenerational product ion distribution, which is then scanned out with a second rf ramp (in the forward direction). Even though, for clarity, the video shows the motion of the precursor and first and second generation fragment ions as distinct events, these events are all occurring in the course of a single RF scan.